IN THE CLAIMS:

Amend claims 1-3, cancel claims 4-9 without prejudice or admission and add new claims 10-13 as shown in the following listing of claims, which replaces all previous listings and versions of claims.

1. (currently amended) An electrical property evaluation apparatus for measuring an electrical property of an object ~~to be measured~~, comprising:

a magnetic field generating mechanism ~~for generating~~ that generates a magnetic field in a target area on ~~the~~ an object to be measured;

a magnetic sensor for measuring the magnetic field near the target area;

a ~~contact~~ cantilever having a conducting probe, the ~~contact~~ cantilever being supported so that the probe can be brought into contact with the target area;

a moving mechanism that moves the cantilever relative to the object to carry our scanning while keeping the probe in contact with the object;

a bending measurement mechanism that measures an amount of bending of the cantilever when the probe is brought into contact with the object;

a control section that controls the moving mechanism so as to maintain the bending amount of the cantilever constant;

a voltage source for applying a voltage to the probe; and

an electrical property measuring section ~~for measuring~~ that measures a current or an electrical resistance between the probe and the object in contact with each other.

2. (currently amended) ~~The~~ An electrical property evaluation apparatus ~~of~~ according to claim ~~1,~~ 1; wherein the magnetic field generating mechanism includes a pair of magnetic field coils, each magnetic field coil having a magnetic pole member, and the magnetic field coils being located opposite to each other, and

the magnetic sensor and ~~contact~~ the cantilever are located in a center location between the pair of magnetic pole members.

3. (currently amended) ~~The~~ An electrical property evaluation apparatus ~~of~~ according to claim ~~2,~~ 2; wherein the pair of magnetic pole members are shaped into a rod or strip form and ~~located with~~ disposed at an inclination relative to a surface of the target area with tips thereof facing ~~to~~ toward the target area.

4.- 9. (canceled).

10. (new) An electrical property evaluation apparatus for measuring an electrical property of an object, comprising:

a magnetic field generating mechanism that generates a magnetic field in a target area of an object to be measured, the magnetic field generating mechanism including a pair of spaced-apart magnetic field coils each having a magnetic pole member;

a magnetic sensor for measuring the magnetic field near the target area;

a contact having a conducting probe and being supported so that the probe can be brought into contact with the target area, the contact and the magnetic sensor being located in a center region between the pair of magnetic pole members;

a voltage source for applying a voltage to the probe; and

an electrical property measuring section that measures a current or an electrical resistance between the probe and the object in contact with each other.

11. (new) An electrical property evaluation apparatus according to claim 10; wherein the pair of magnetic pole members have an elongate shape and are disposed at an inclination relative to a surface of the target area such that tips of the magnetic pole members face toward the target area.

12. (new) An electrical property evaluation apparatus according to claim 11; wherein the contact is bendable; and further including a moving mechanism that scans the contact relative to the object while keeping the probe in contact with the object; a bending measurement mechanism that measures an amount of bending of the contact when the probe is brought into contact with the object; and a control section that controls the moving mechanism so as to maintain the bending amount of the contact constant.

13. (new) An electrical property evaluation apparatus according to claim 10; wherein the contact is bendable; and further including a moving mechanism that scans the contact relative to the object while keeping the probe in contact with the object; a bending measurement mechanism that measures an amount of bending of the contact when the probe is brought into contact with the object; and a control section that controls the moving mechanism so as to maintain the bending amount of the contact constant.